

# MBN800E33D

Silicon N-channel IGBT

## FEATURES

- \* High speed, low loss IGBT module.
- \* Low driving power due to low input capacitance MOS gate.
- \* Low noise due to ultra soft fast recovery diode.
- \* High reliability, high durability module.
- \* High thermal fatigue durability.  
( $\Delta T_c=70^\circ\text{C}$ ,  $N>30,000$ cycles)
- \* Isolated heat sink (terminal to base).

## ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ\text{C}$ )

Item	Symbol	Unit	MBN800E33D
Collector Emitter Voltage	$V_{CES}$	V	3,300
Gate Emitter Voltage	$V_{GES}$	V	$\pm 20$
Collector Current	DC	$I_C$	800
	1ms	$I_{Cp}$	1,600
Forward Current	DC	$I_F$	800
	1ms	$I_{FM}$	1,600
Junction Temperature	$T_j$	$^\circ\text{C}$	-40 ~ +125
Storage Temperature	$T_{stg}$	$^\circ\text{C}$	-40 ~ +125
Isolation Voltage	$V_{ISO}$	$V_{RMS}$	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value  $1.8\pm 0.2/15^{+0}_{-3}1\text{N}\cdot\text{m}$ (2) Recommended Value  $5.5\pm 0.5\text{N}\cdot\text{m}$ 

## ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	$I_{CES}$	mA	-	-	12.0	$V_{CE}=3,300\text{V}$ , $V_{GE}=0\text{V}$ , $T_j=25^\circ\text{C}$
			-	14	40	$V_{CE}=3,300\text{V}$ , $V_{GE}=0\text{V}$ , $T_j=125^\circ\text{C}$
Gate Emitter Leakage Current	$I_{GES}$	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}$ , $V_{CE}=0\text{V}$ , $T_j=25^\circ\text{C}$
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	3.5	4.2	5.0	$I_C=800\text{A}$ , $V_{GE}=15\text{V}$ , $T_j=125^\circ\text{C}$
Gate Emitter Threshold Voltage	$V_{GE(TO)}$	V	4.5	6.0	7.0	$V_{CE}=10\text{V}$ , $I_C=800\text{mA}$ , $T_j=25^\circ\text{C}$
Input Capacitance	$C_{ies}$	nF	-	75	-	$V_{CE}=10\text{V}$ , $V_{GE}=0\text{V}$ , $f=100\text{kHz}$ , $T_j=25^\circ\text{C}$
Internal Gate Resistance	$R_{g(int)}$	$\Omega$	-	1.8	-	$V_{CE}=10\text{V}$ , $V_{GE}=0\text{V}$ , $f=100\text{kHz}$ , $T_j=25^\circ\text{C}$
Switching Times	Rise Time	$t_r$	1.0	1.9	3.1	$V_{CC}=1,650\text{V}$ , $I_C=800\text{A}$
	Turn On Time	$t_{on}$	1.1	2.4	3.3	$L=120\text{nH}$
	Fall Time	$t_f$	0.4	1.0	2.5	$R_G=4.7\Omega$ (3)
	Turn Off Time	$t_{off}$	1.9	3.0	5.1	$V_{GE}=\pm 15\text{V}$ , $T_j=125^\circ\text{C}$
Peak Forward Voltage Drop	$V_{FM}$	V	1.7	2.5	3.0	$I_F=800\text{A}$ , $V_{GE}=0\text{V}$ , $T_j=125^\circ\text{C}$
Reverse Recovery Time	$t_{rr}$	$\mu\text{s}$	0.3	0.6	1.1	$V_{CC}=1,650\text{V}$ , $I_F=800\text{A}$ , $L=120\text{nH}$ $T_j=125^\circ\text{C}$
Turn On Loss	$E_{on(10\%)}$	J/P	-	1.2	1.6	$V_{CC}=1,650\text{V}$ , $I_C=800\text{A}$ , $L=120\text{nH}$
Turn Off Loss	$E_{off(10\%)}$	J/P	-	0.8	1.2	$R_G=4.7\Omega$ (3)
Reverse Recovery Loss	$E_{rr(10\%)}$	J/P	-	0.9	1.3	$V_{GE}=\pm 15\text{V}$ , $T_j=125^\circ\text{C}$
Stray inductance module	$L_{SCE}$	nH	-	18	-	
Thermal Impedance	IGBT	$R_{th(j-c)}$	-	-	0.013	Junction to case
	FWD	$R_{th(j-c)}$	-	-	0.026	
Contact Thermal Impedance	$R_{th(c-f)}$	K/W	-	0.008	-	Case to fin

Notes:(3)  $R_G$  value is a test condition value for evaluation, not recommended value.Please, determine the suitable  $R_G$  value by measuring switching behaviors.

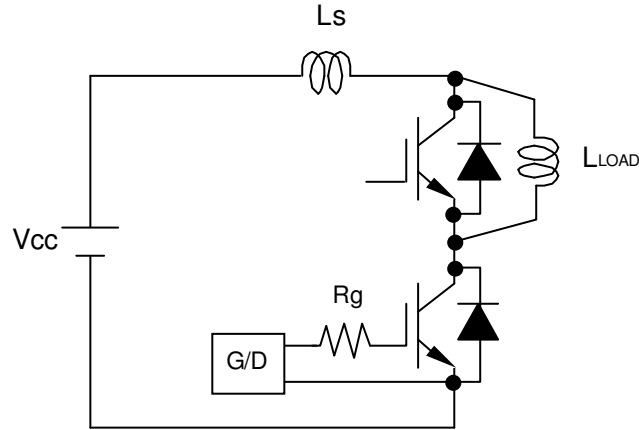
\* Please contact our representatives at order.

\* For improvement, specifications are subject to change without notice.

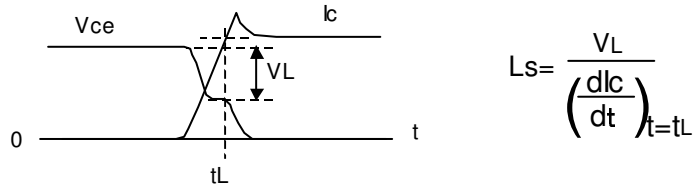
\* For actual application, please confirm this spec sheet is the newest revision.

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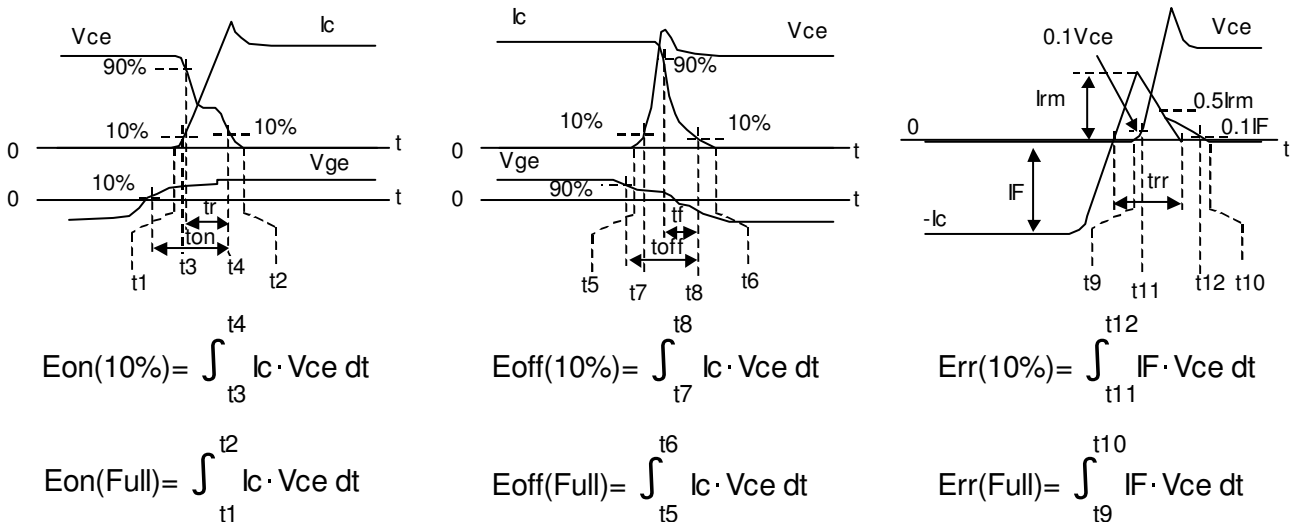
## DEFINITION OF TEST CIRCUIT



**Fig.1 Switching test circuit**



**Fig.2 Definition of Ls**

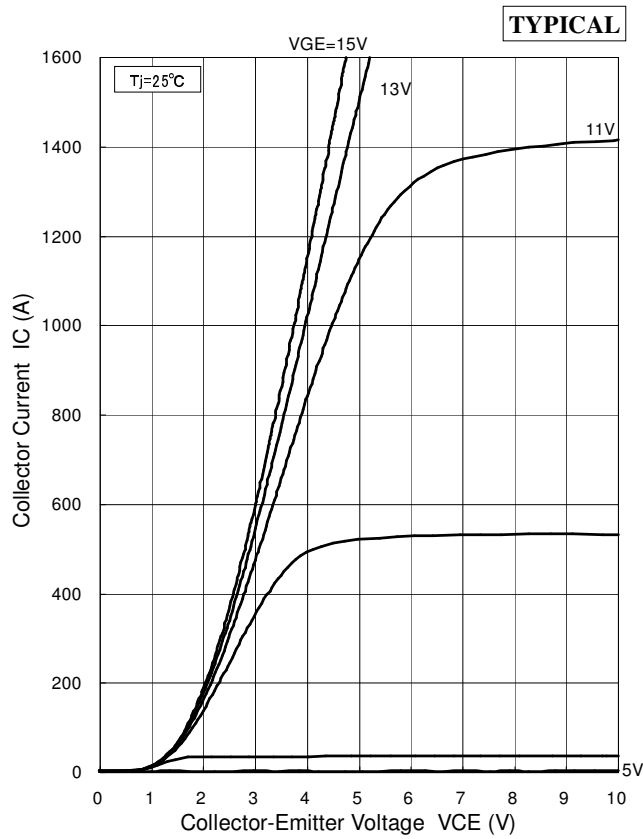


**Fig.3 Definition of switching loss**

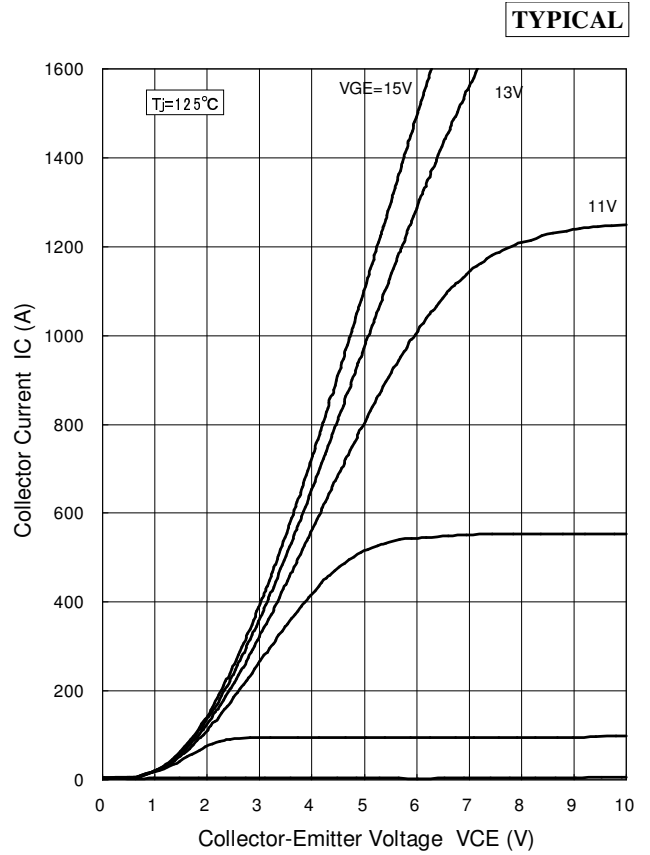
# MBN800E33D

## CHARACTERISTICS CURVE

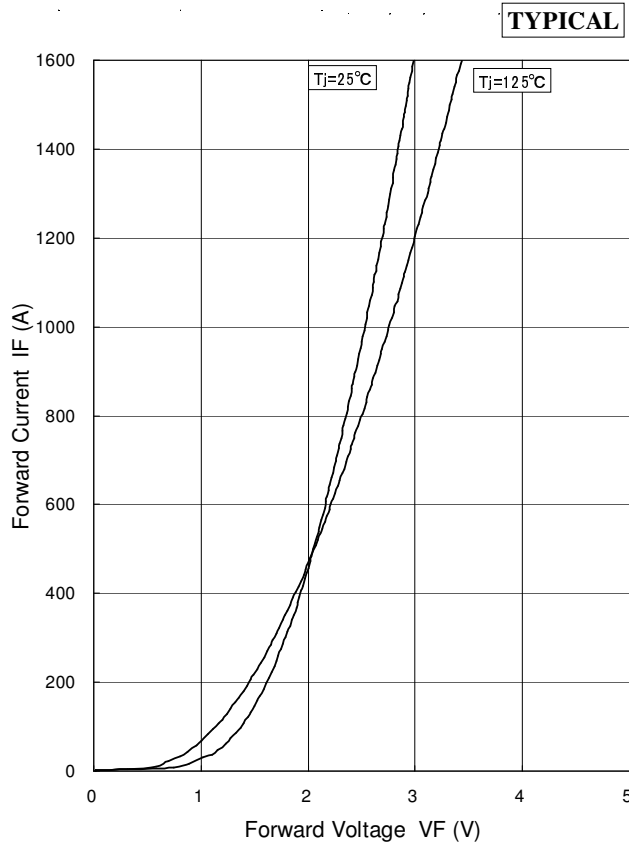
### STATIC CHARACTERISTICS



Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage

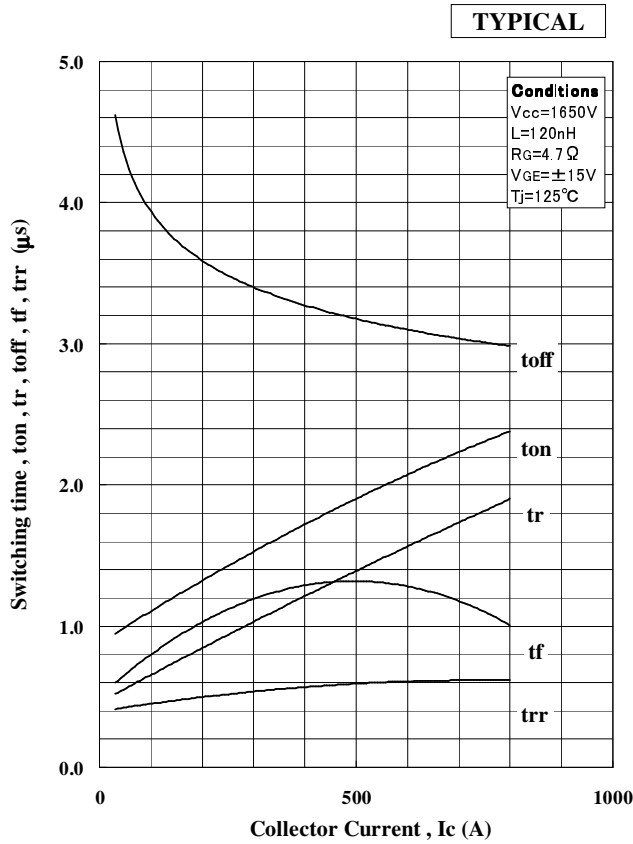


Forward Voltage of free-wheeling diode

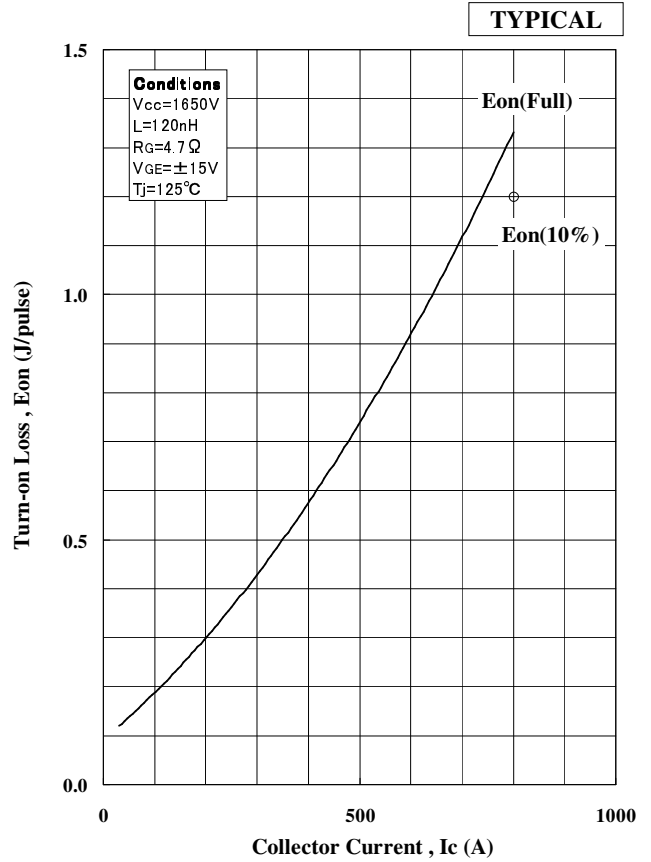
# MBN800E33D

## DYNAMIC CHARACTERISTICS

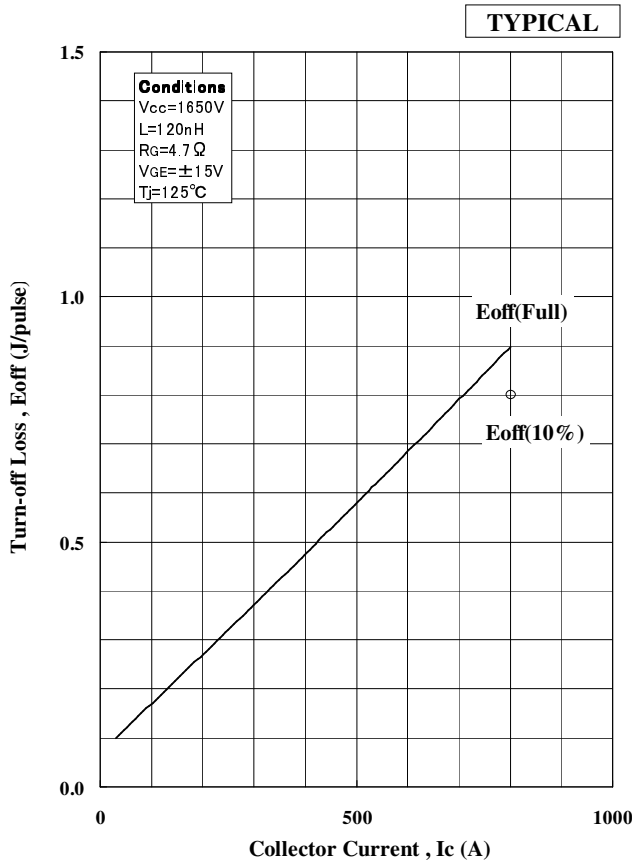
### DEPENDENCE OF CURRENT



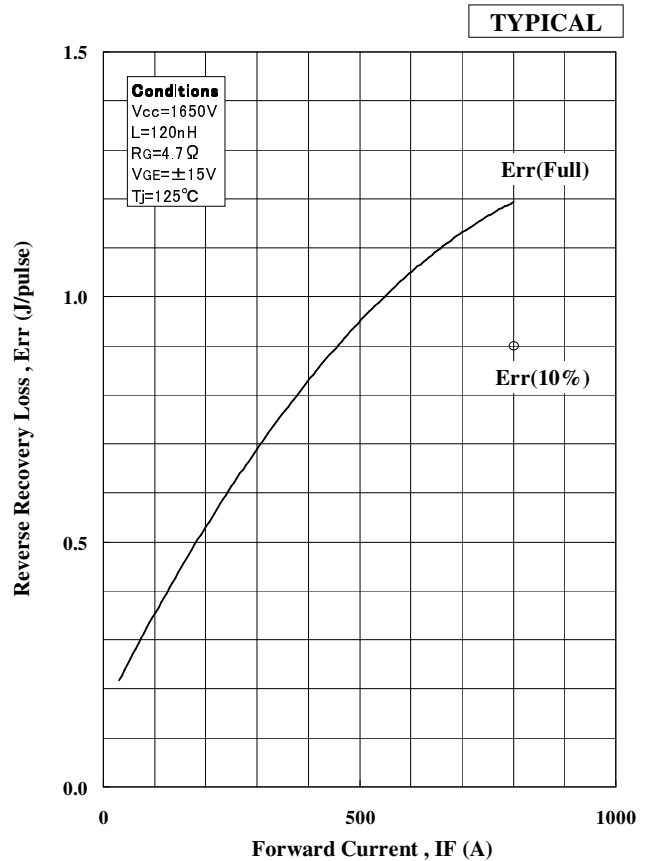
Turn-on Loss vs. Collector Current



Turn-on Loss vs. Collector Current



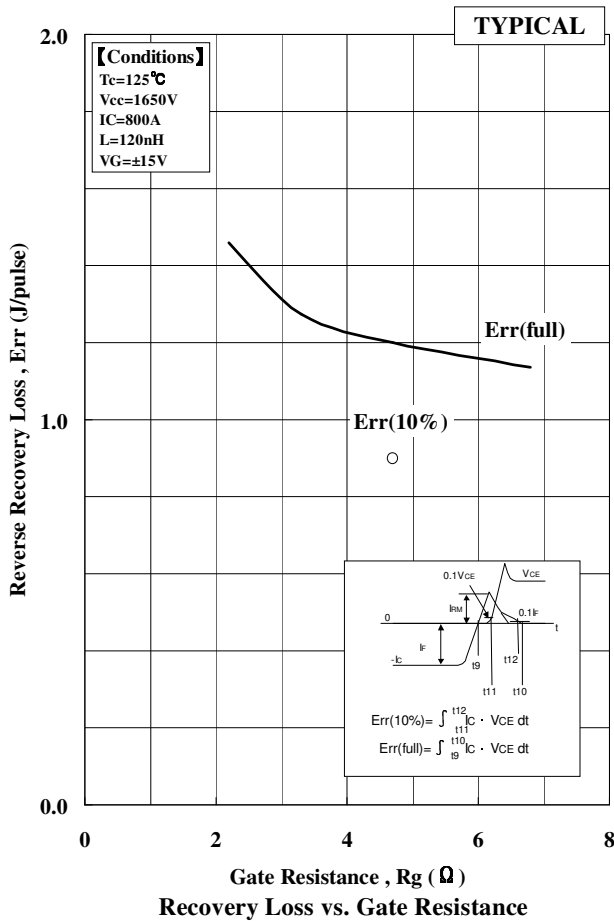
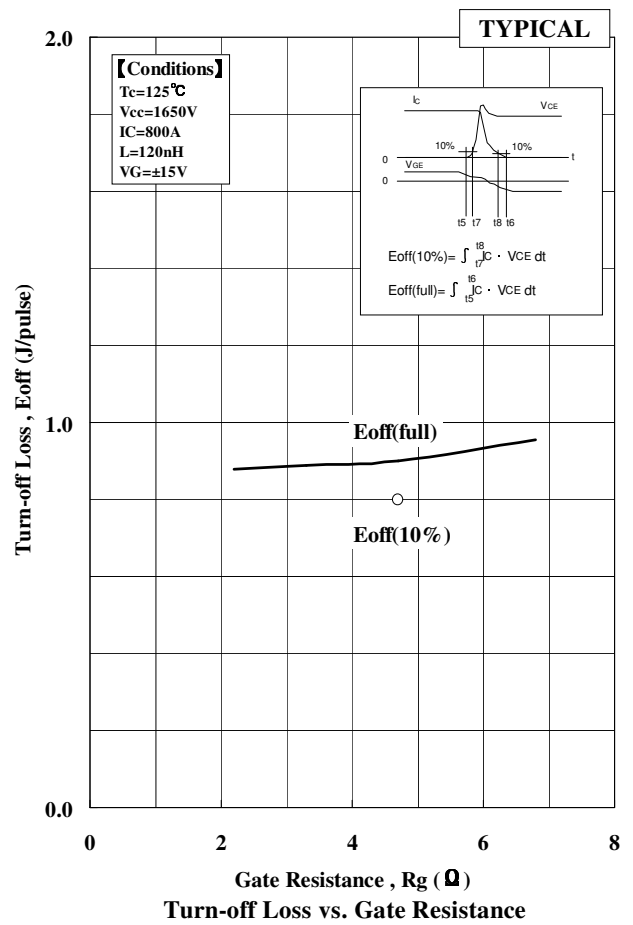
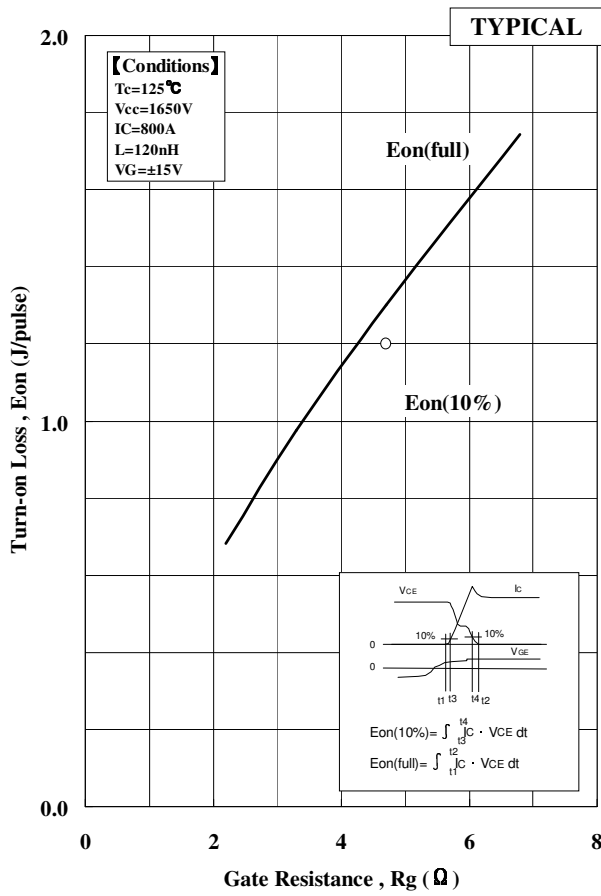
Turn-off Loss vs. Collector Current



Reverse Recovery Loss vs. Forward

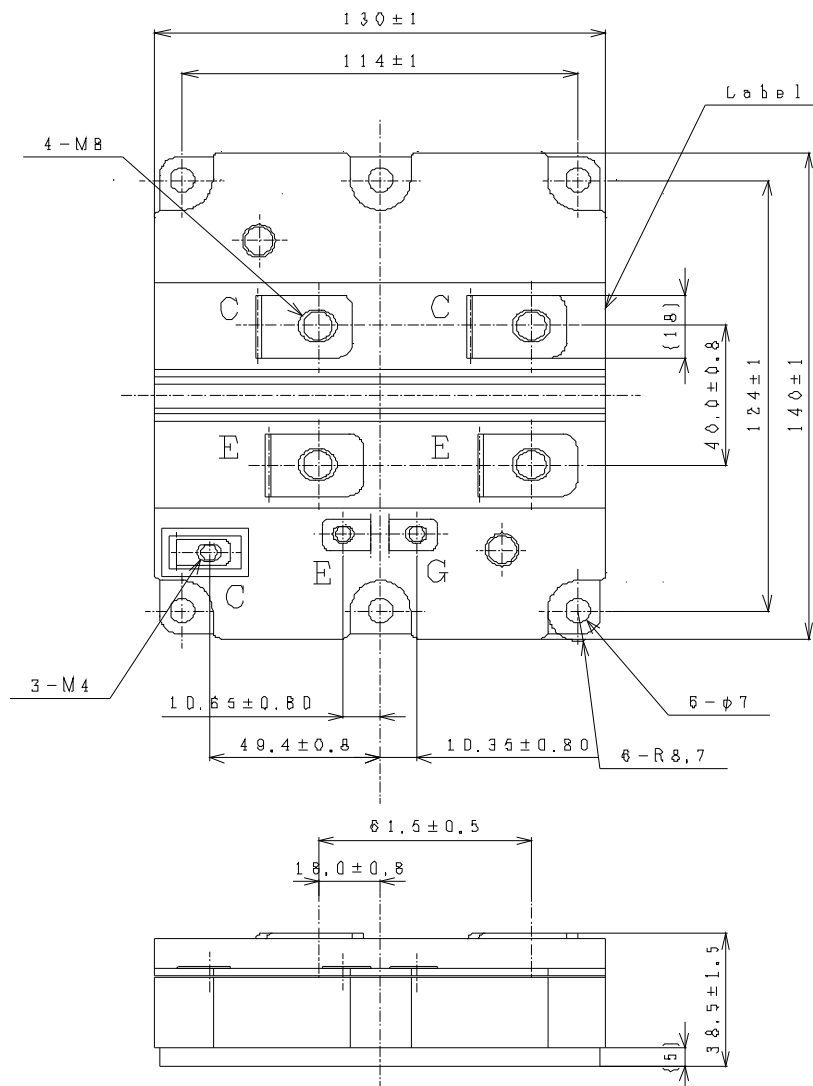
# MBN800E33D

## DEPENDENCE OF RG

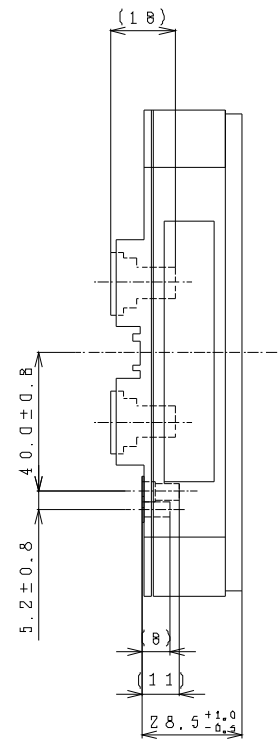


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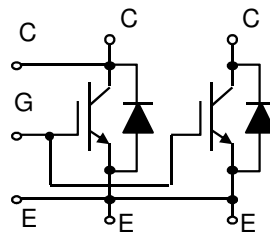
## OUTLINE DRAWINGS



Unit in mm



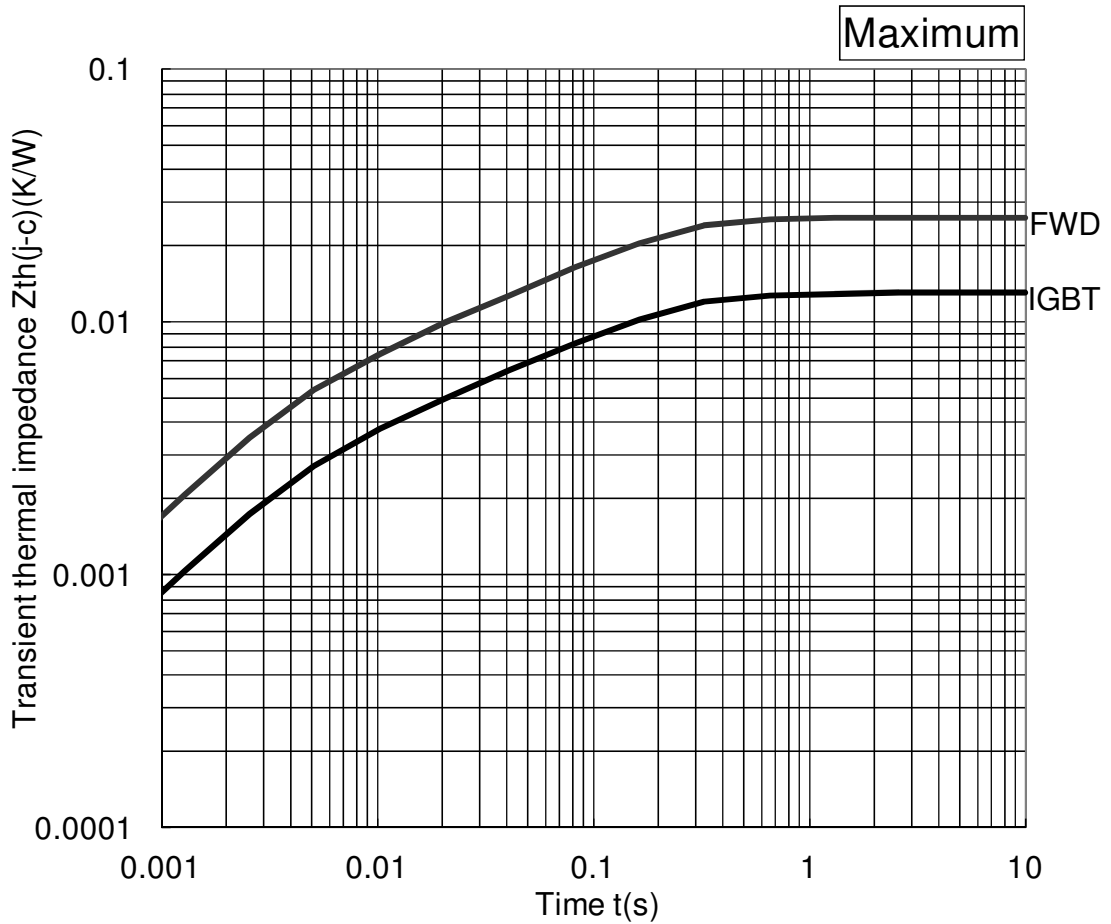
Weight: 900(g)



Circuit diagram

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**TRANSIENT THERMAL IMPEDANCE**



Transient Thermal Impedance Curve

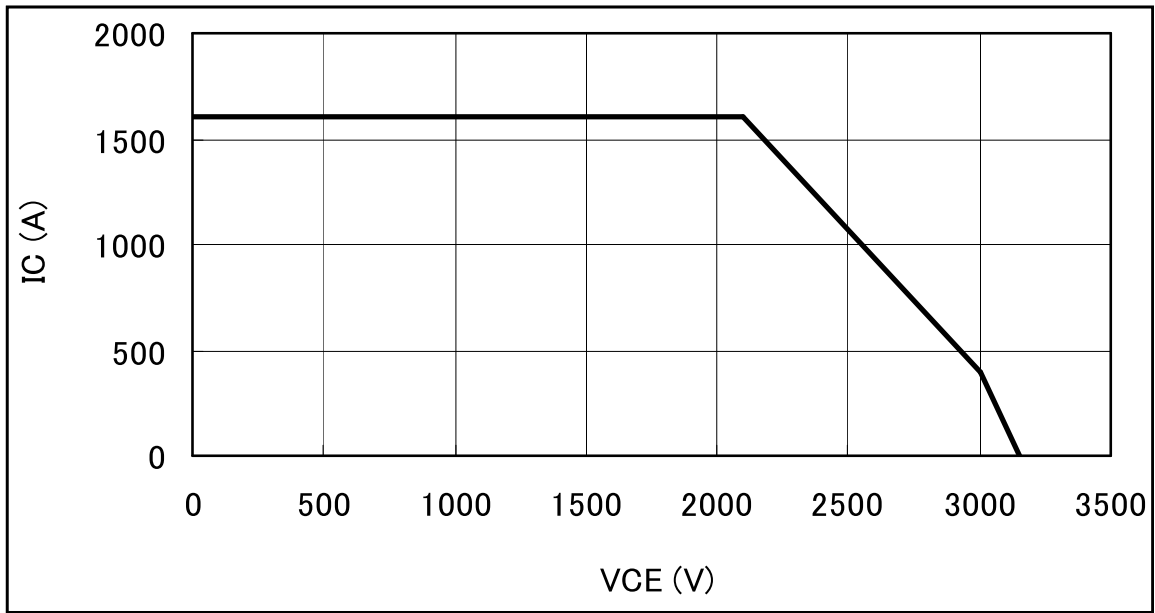
**Material declaration**

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

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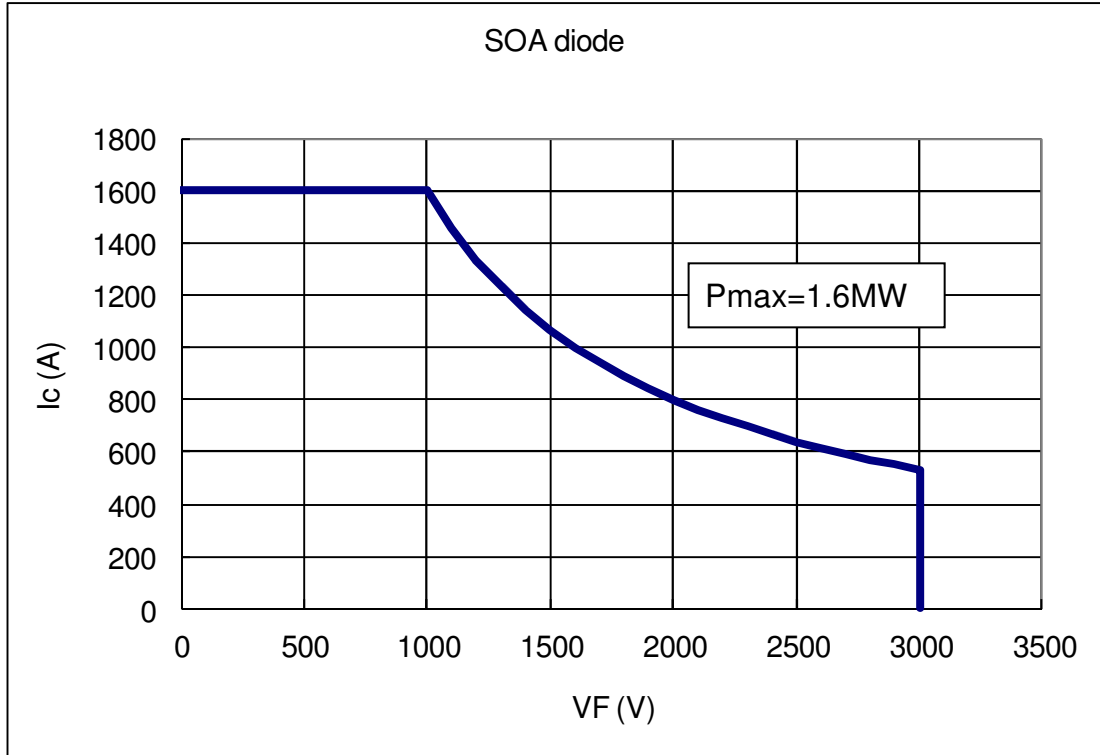
SOA  
RBSOA



RBSOA diagram

RBSOA  
Hitachi routine test conditions  
 $T_j=125^{\circ}\text{C}$ ,  $V_{cc}=2000\text{V}$ ,  $I_c=1600\text{A}$ ,  $L_s=120\text{nH}$ ,  $V_{GE}=\pm 15\text{V}$ ,  $R_G=4.7\Omega$   
(Measured at auxiliary terminal)

Recovery SOA



RecSOA diagram

RecSOA  
Hitachi routine test conditions  
 $T_j=125^{\circ}\text{C}$ ,  $V_{cc}=2000\text{V}$ ,  $I_F=1600\text{A}$ ,  $L_s=120\text{nH}$ ,  $V_{GE}=\pm 15\text{V}$ ,  $R_G=4.7\Omega$   
(Measured at auxiliary terminal)



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## HITACHI POWER SEMICONDUCTORS

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